

Form PTO 1449

U.S. DEPARTMENT OF
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OFFICE

(Modified)

ATTY. DOCKET NO.

8733.20069

SERIAL NO.

09/446,330

APPLICANT

Victor A. KONOVALOV et al.

LIST OF REFERENCES CITED BY APPLICANT
(Use Several Sheets if Necessary)

FILING DATE

March 23, 2000

GROUP

TBA

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
Q	AA	5,249,070	09/1993	Takano	359	54	10/15/1991
Q	AB	5,309,264	05/1994	Lien et al.	359	87	04/30/1992
	AC						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO
	AD				

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

Q	AE	SID 93 DIGEST, 19.2 "Two-Domain TN-LCDs Fabricated by Parallel Fringe Field Method," by A. Lien and R.A. John, IBM T.J. Watson Research Center, Yorktown Heights, NY., pp. 269-72
Q	AF	SID 94 DIGEST, P45: "TFT-Addressed Two-Domain TN VGA Displays Fabricated Using the Parallel-Fringe-Field Method," by A. Lien, R.A. John, IBM T.J. Watson Research Center, Yorktown Heights, NY, pp. 594-7
Q	AG	SID 95 DIGEST, 41.2 "No-Rub Multi-Domain TFT-LCD Using Surrounding-Electrode Method," by N. Koma, Y. Baba and K. Matsuoka, Sanyo Electric Co., Ltd., Gifu, Japan, pp. 869-72
Q	AH	Euro Display '96, 11.3 "Novel high contrast random and controlled 4-domain CTN-LCDs with wide viewing angle," by H. Murai, M. Suzuki and S. Kaneko, NEC Corp., Kawasaki, Japan, pp. 159-61
Q	AI	IDW '97, "A Vertically Aligned LCD Providing Super-High Image Quality," by Y. Koike, S. Kataoka, T. Sasaki, H. Chida, H. Tsuda, A. Takeda and K. Ohmuro, Fujitsu Limited, pp. 159-62
Q	AJ	SID 97 DIGEST, P-1 "Development of a High-Quality TFT-LCD for Projection Displays," N. Koma and R. Nishikawa, Sanyo Electric Co., Ltd., Gifu, Japan, pp. 461-4
Q	AK	SID 97 DIGEST, 33.3 "Development of Super-High-Image-Quality Vertical-Alignment-Mode LCD," by K. Ohmuro, S. Kataoka, T. Sasaki and Y. Koike, Fujitsu Ltd., Atsugi, Japan, pp. 845-8

EXAMINER

DATE CONSIDERED 10/21/02

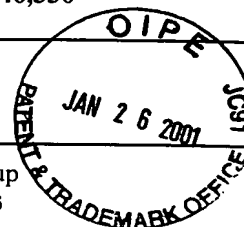
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Attorney Docket No.
8733.176.00Application No.
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Sergey E. Yakovenko, et al.Filing Date
March 23, 2000Group
2713

Date: January 26, 2001



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EXAMINER INITIAL*		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
⑤	AA	3,914,022	10/21/75	Kashnow			
①	AB	4,581,608	04/08/86	Aftergut, et al.			
⑨	AC	4,701,028	10/20/87	Clerc, et al.			
⑨	AD	4,728,175	03/01/88	Baron			
①	AE	4,786,147	11/22/88	Clerc, et al.			
⑨	AF	4,889,412	12/26/89	Clerc, et al.			
⑨	AG	4,937,566	06/26/90	Clerc			
①	AH	4,978,203	12/18/90	Yamazaki, et al.			
⑨	AI	5,039,185	08/13/91	Uchida, et al.			
①	AJ	5,093,741	03/03/92	Shohara, et al.			

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		Document No.	Date	Country	TRANSLATION	
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⑤	AK	2 296 810 (A)	07/10/96	Great Britain	X	
⑤	AL	2 321 718 (A)	08/05/98	Great Britain	X	
⑤	AM	2 337 843 (A)	12/01/99	Great Britain	X	
⑤	AN	0 752 611 (A2)	01/08/97	European Patent Office	X	
⑤	AO	0 814 142 (A2)	12/29/97	European Patent Office	X	
⑤	AP	0 854 377 (A2)	07/22/98	European Patent Office	X	
⑤	AQ	0 884 626 (A2)	12/16/98	European Patent Office	X	

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

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Examiner Signature	Date Considered: C/30/03

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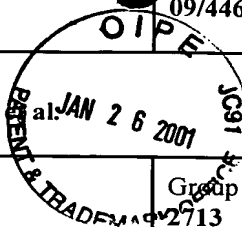
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Q	AA	5,182,664	01/26/93	Clerc			
Q	AB	5,229,873	07/20/93	Hirose, et al.			
Q	AC	5,339,181	08/16/94	Kim, et al.			
Q	AD	5,477,358	12/19/95	Rosenblatt, et al.			
Q	AE	5,517,341	05/14/96	Kim, et al.			
Q	AF	5,517,342	05/14/96	Kim, et al.			
Q	AG	5,574,582	11/12/96	Takeda, et al.			
Q	AH	5,602,662	02/11/97	Rosenblatt, et al.			
Q	AI	5,608,556	03/04/97	Koma			

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		Document No.	Date	Country	TRANSLATION	
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Q	AJ	02-294622	12/05/90	JAPAN	ABSTRACT	
Q	AK	03-261914	11/21/91	JAPAN	ABSTRACT	
Q	AL	04-067127	03/03/92	JAPAN	ABSTRACT	
Q	AM	04-261522	09/17/92	JAPAN	ABSTRACT	
Q	AN	05-002161	01/08/93	JAPAN	ABSTRACT	
Q	AO	05-297412	11/12/93	JAPAN	ABSTRACT	
Q	AP	06-194656	07/15/94	JAPAN	ABSTRACT	

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

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2713Date: January 26, 2001

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Q	AA	5,621,558	04/15/97	Shimada, et al.			
Q	AB	5,623,354	04/22/97	Lien, et al.			
Q	AC	5,666,179	09/09/97	Koma			
Q	AD	5,668,650	09/16/97	Mori, et al.			
Q	AE	5,673,092	09/30/97	Horie, et al.			
Q	AF	5,686,977	11/11/97	Kim, et al.			
Q	AG	5,737,051	04/07/98	Kondo, et al.			
Q	AH	5,767,926	06/16/98	Kim, et al.			
Q	AI	5,777,701	07/07/98	Zhang			
Q	AJ	5,777,711	07/07/98	Sugiyama			

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Q	AK	06-194657	07/15/94	JAPAN	ABSTRACT	
Q	AL	06-258649	09/16/94	JAPAN	ABSTRACT	
Q	AM	06-273798	09/30/94	JAPAN	ABSTRACT	
Q	AN	06-281959	10/07/94	JAPAN	ABSTRACT	
Q	AO	06-301036	10/28/94	JAPAN	ABSTRACT	
Q	AP	06-347824	12/22/94	JAPAN	ABSTRACT	
Q	AQ	07-013164	01/17/95	JAPAN	ABSTRACT	

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8733.176.00

Application No.

09/446,320

Applicant
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March 23, 2000

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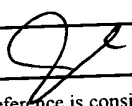
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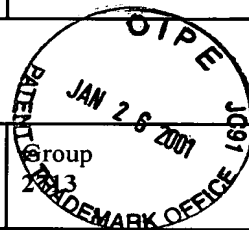
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FOREIGN PATENT DOCUMENTS

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0	AB	08-313915	11/29/96	JAPAN	ABSTRACT	
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0	AD	09-033890	02/07/97	JAPAN	ABSTRACT	
0	AE	09-152583	06/10/97	JAPAN	ABSTRACT	
0	AF	09-197420	07/31/97	JAPAN	ABSTRACT	
0	AG	09-230360	09/05/97	JAPAN	ABSTRACT	
0	AH	09-230387	09/05/97	JAPAN	ABSTRACT	
0	AI	09-236821	09/09/97	JAPAN	ABSTRACT	
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0	AK	10-301112	11/13/98	JAPAN	ABSTRACT	
0	AL	10-333180	12/18/98	JAPAN	ABSTRACT	
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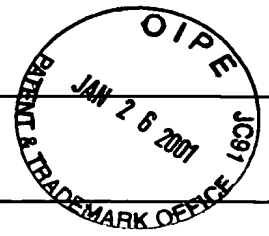
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Form PTO 1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT (Use Several Sheets if Necessary)	Attorney Docket No. 8733.176.00	Application No. 09/446,330
	Applicant Sergey E. Yakovenko, et al.	
Date: <u>January 26, 2001</u>	Filing Date March 23, 2000	Group 2713



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	Document No.	Date	Country	TRANSLATION	
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A	AB	11-119198	JAPAN	ABSTRACT	
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D	AF	11-149079	JAPAN	ABSTRACT	
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